ZAF CORRECTION METHOD

The ZAF correction method determines the mass concentration C_A of an element A from the following equation:

$$C_{A}^{UNK} = K_{A}^{UNK} \times G_{Z} \times G_{A} \times G_{F}$$

$$= K_{A}^{UNK} \times \frac{R_{A}^{STD} \times P_{A}^{STD}}{R_{A}^{UNK} \times P_{A}^{UNK}} \times \frac{f_{A}^{STD}(\chi_{A})}{f_{A}^{UNK}(\chi_{A})} \times \frac{1}{1 + \frac{I_{A}(f)}{I_{A}(d)}}$$

where $K_A^{UNK} = \frac{I_A^{UNK}}{I_A^{STD}}$ and I_A are the X-ray intensities (in cps) per unit current of element A after dead-time correction and background correction; UNK indicates the unknown sample; STD indicates the standard sample; and G_z, G_A, and G_F are atomic-number correction coefficient, absorption correction coefficient, and fluorescence correction coefficient, respectively.

The following are brief descriptions of atomic-number correction, absorption correction, and fluorescence correction.

• Atomic number correction (Z)

Atomic-number correction deals with differences in the behavior of incident electrons between an unknown sample and a standard sample. This correction is usually considered in two factors: the P factor, including the stopping power term, which indicates penetration of electrons into the sample, and the R factor which indicates the backscattering of electrons from the sample. The two factors tend to cancel each other, so that the correction factors are not very large in most cases.

Absorption correction (A)

Absorption correction deals with differences in the degree of X-ray absorption between an unknown sample and a standard sample. This correction gives consideration to the mass absorption coefficient, incident electron energy, and X-ray take-off angle.

• Fluorescence correction (F)

Fluorescence correction needs to be considered if the characteristic X-rays from an element, B, are at the short-wavelength (high-energy) side of the absorption edge of another element, A. In this case, the X-rays from element B may excite element A. The same is true with fluorescence excitation by continuous X-rays, but the effect usually is negligible.

2.4.1 Atomic Number Correction

The basic equation of atomic number correction is

$$G_Z = \frac{R^{STD}}{R^{UNK}} \times \frac{P^{STD}}{P^{UNK}}$$

where R is the backscattering factor and P is the penetration factor. The backscattering factor of an unknown sample is determined from:

$$R = \sum_{j} C_{j} R_{ji}$$

$$R_{ii} = R(Z_i, U_i)$$

where C_i : concentration of element j, $\Sigma C_i = 1$

Z_i: atomic number of element in matrix

 U_i : over-voltage ratio (= E_0/E_{Ki})

E_{Ki}: K-shell excitation energy of element i

E₀: accelerating voltage

The value R_{ji} is determined by calculating the values*, that are given by Duncumb-Reed, through the method of least squares:

$$\begin{split} R(Z_j,U_i) = & 1 - X \cdot V \Big[-0.187204 + 1.67366V - 1.51187V^2 + 0.707063V^3 \\ & \quad + X \Big\{ 3.63547 - 1.9914V - 1.6539V^2 + 0.477246V^3 \Big\} \\ & \quad + X^2 \Big\{ -4.04514 - 4.11268V + 9.26509V^2 - 2.79199V^3 \Big\} \\ & \quad + X^3 \Big\{ 1.54054 + 3.43134V - 5.22007V^2 + 1.23353V^3 \Big\} \ \Big] \end{split}$$

where $X = Z_i/100$, $V = 1 - 1/U_i$

The penetration factor P_i is given by

$$P_{i} = \frac{1}{M} \left[\left(U_{i} - 1 \right) \frac{1}{W_{i}} lnW_{i} \left\{ Li \left(U_{i} W_{i} \right) - Li \left(W_{i} \right) \right\} \right]$$

where Li (x) is a logarithmic differential function expressed as

$$Li(x) = C + ln |ln x| + \sum_{r=1}^{\infty} \frac{(lnx)^r}{r \cdot r!}$$
 C: Euler's constant

$$lnW_i = \frac{1}{M} \sum_j C_j \frac{Z_j}{A_j} ln \frac{1.166E_{Ki}}{J_j}$$
 i: emitter, j: absorber

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^{*} P. Duncumb. and S. J. B. Reed, NBS Special Publication, 298, P. 133 (1968)

$$M = \sum_{j} C_{j} \frac{Z_{j}}{A_{j}}$$

A_i: atomic weight of element j

J_j: average ionization potential of element J (eV)

$$J_j = 9.76Z_j + 58.8Z_j^{-0.19}$$
 (Berger-Seltzer*)
= $Z_j \left(9.76 + 58.8Z_j^{-1.19} \right)$

For each element, the atomic weight is given in the file atom.asc in the directory /opt/epma/phys, while the excitation energy is given in the file abs_edge.dat in the same directory.

^{*} M. J. Berger and S. M. Seltzer, Nat. Acad. Sci., Nat. Res. Counc. Publ. 1133, P. 205 (1964)

2.4.2 Absorption Correction

Absorption correction uses the following Philibert formula:

$$f(x) = \frac{1+h}{\left(1+\frac{x}{\sigma}\right)\left\{1+h\left(1+\frac{x}{\sigma}\right)\right\}}$$

where

$$h = 1.2 \frac{A}{Z^2}$$

A: atomic weight

Z: atomic number

$$\sigma = \frac{4.5 \times 10^5}{E_0^{1.65} - E_K^{1.65}}$$
 (Lenard's coefficient)

E₀: accelerating voltage (in keV)

E_K: K-shell excitation energy (in keV)

$$x = (\mu / \rho) \csc \theta$$

θ: X-ray take-off angle

 μ/ρ : mass absorption coefficient

The mass absorption coefficient is determined as follows:

- Z < 10 (wavelength λ is more than 12Å): The values given by Henke* are used.
- $Z \ge 10$ (wavelength λ is 12Å to 0.7Å): The values calculated by Heinrich method** are used.

Heinrich method

• The mass absorption coefficient of characteristic X-rays (radiation) from an element for the absorber is given as:

$$\mu / \rho = C_i(Z) \lambda_R n_i(Z)$$

where $C_i(Z)$ and $n_i(Z)$ are values that depend on the atomic number (Z) of the absorber. The value i varies with the relation between the X-ray wavelength λ_R and the absorber's absorption edge.

• The wavelengths and coefficients needed for calculation are as follows:

Wavelength as a function of Z:

wavelength of X-rays ($K\alpha$, $K\beta$, $L\alpha$, $L\beta$, $M\alpha$,

 $M\beta$)

Absorber as a function of Z:

wavelength of absorption edge (K, L_1 , L_2 ,

 L_3 , M_1 , M_2 , M_3 , M_4 , M_5)

coefficient C_i (C_K, C_{KL}, C_{L1}, C_{L2}, C_{LM}, C_{M1},

 C_{M2} , C_{M3} , C_{M4} , C_{MN})

coefficient n_i (n_K, n_{KL}, n_{LM}, n_{MN})

^{*} B. L. Henke, Adv. X-ray Anal., 9, 460 (1966)

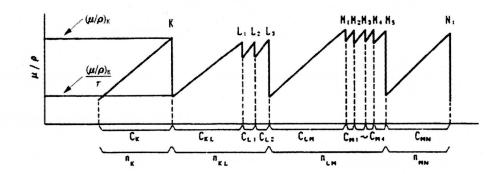
B. L. Henke et al., Atomic Data and Nuclear DataTables, vol 27, No.1 (1982)

^{*} K. F. J. Heinrich, The Electron Probe (New York, Wiley), P. 296 (1966)

All of these values are approximated by the quartic equation for the atomic number:

$$X = \exp \left\{ A(0) + A(1)Y + A(2)Y^{2} + A(3)Y^{3} + A(4)Y^{4} \right\}$$
where
$$Y = \ln(Z)$$
A (i): constant

• The suffix i in $C_i(Z)$ and $n_i(Z)$ is determined by placing the absorption edges relative to the order of wavelength and identifying the positions of wavelength, λ_R , of characteristic X-rays, as shown below.



- The values C_i and n_i are given in a table by Heinrich. The constants for A (0) to A (4) are determined so that they may come close to the values in the table. However, C_{M4} is unknown.
- In C_i , the values C_{L1} and C_{L2} are proportional to C_{KL} , while the values C_{M1} , C_{M2} , C_{M3} and C_{M4} are proportional to C_{LM} . Therefore, only C_K , C_{KL} , C_{LM} and C_{MN} are calculated in the quartic equation; the others are determined by multiplying them with the proportional constants.
- \angle For n_i , Heinrich always specifies $n_{LM} = 2.6$ and $n_{NM} = 2.22$.
- The values for the absorption edge and wavelength are also calculated with the quartic equation of Z.

These mass absorption coefficient values are stored in the following files in the directory /opt/epma/phys/mac: Ka.mac, Kb.mac, Lb.mac, Ma.mac, and Mb.mac.

2.4.3 Fluorescence Correction

Fluorescence correction usually refers to determining the value ${}^{fl}\gamma_A$ in the equation below. Assuming the specimen is a binary element system in which element A is excited by element B, we have:

$${}^{fl}\gamma_{A} = \frac{I_{A}(f)}{I_{A}(d)} = \frac{1}{2}C_{B}\frac{r_{K}^{A} - \ln(\mu/\rho)_{B}^{A}}{r_{K}^{A}(\mu/\rho)_{B}^{AB}}W_{K}^{B}\frac{A_{A}}{A_{B}}\left(\frac{U_{0}^{B} - 1}{U_{0}^{A} - 1}\right)^{1.67}\left\{\frac{\ln(1+x)}{x} + \frac{\ln(1+y)}{y}\right\}$$

where

I_A (d): intensity of primary X-rays of element A subject to direct excitation

I_A (f): intensity of X-rays due to fluorescence excitation of the other element B

C_B: concentration of element B

 r_{ν}^{A} : absorption edge jump factor for element A

 $(\mu/\rho)_{R}^{AB}$: specimen's mass absorption coefficient for X-rays from element B

 $(\mu/\rho)_{R}^{A}$: element A's mass absorption coefficient for X-rays from element B

 W_K^B : K-shell fluorescence absorption rate of element B

A_A: atomic weight of element A

A_B: atomic weight of element B

$$U_0^A = E_0 / E_K(A)$$

$$U_0^B = E_0 / E_K(B)$$

$$x = \left\{ \left(\mu / \rho \right)_A^{AB} / \left(\mu / \rho \right)_B^{AB} \right\} \operatorname{cosec} \theta$$

$$y = \sigma / (\mu / \rho)_{R}^{AB}$$

Considering the excitation caused by other X-rays, Reed transformed the above equation to the following:

$$f^{I}\gamma = C_{B}J_{A}D\frac{(\mu/\rho)_{B}^{A}}{(\mu/\rho)_{R}^{AB}}\{g(x)+g(y)\}$$

where

$$J(A) = \frac{1}{2} P_{ij} \frac{r_{K(L)}^{A} - 1}{r_{K(L)}^{A}} W_{K(L)}^{A} \frac{A_{A}}{A_{B}}$$

$$D = \left(\frac{U_0^B - 1}{U_0^A - 1}\right)^{1.67}$$

$$g(x) = \frac{\ln(1+x)}{x}$$

P_{ii}: constant related to difference in generation of K-line and L-line

The values J (A) are given by Reed in a table.

The values are stored in the file Reed_JA.dat in the directory /opt/epma/phys.

- Whether fluorescence excitation occurs is checked by comparing the wavelengths at the absorption edges of each element and the wavelengths of all other X-rays generated from other elements.
- Fluorescence excitation can be caused by X-rays not even intended to be measured. This software also takes such X-rays into account in the correction calculations.

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